Application/Control No. Applicant(s)/Patent Under Reexamination 09/921,024 WEIRAUCH ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 TAN X. DINH 2653 **U.S. PATENT DOCUMENTS** Date Document Number Name Classification Country Code-Number-Kind Code MM-YYYY US-2005/0025037 A1 02-2005 Weirauch, Charles R. Α 369/275.3 US-6,130,867 A 10-2000 Ishida et al. 369/275.3 В US-С US-D US-Ε F US-US-G US-Н US-1 US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Code-Number-Kind Code Country Name Classification MM-YYYY N 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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